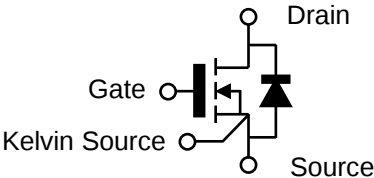


Silicon Carbide MOSFET

650V, 10mΩ SiC MOSFET – Falcon Series



Product Information:



Features

- Optimized $R_{DS(on)}$ with Rapid Switching Behavior
- Compatible with Standard Gate Drivers
- Clean Kelvin-Source Switching Pin-out
- High Avalanche Endurance Capability
- Optimized for High Power Density Applications
- RoHS Compliant and Halogen Free

Terminal	Packaging Type
	TOLL
Gate	1
Drain	Tab
Source	3, 4, 5, 6, 7, 8
Kelvin Source	2

Benefits

- Higher System Efficiency
- Increase Parallel Device Convenience
- Enable High Temperature Application
- Allow High Frequency Operation
- Realize Compact and Lightweight Systems
- High Reliability

Potential Applications

- Switching Mode Power Supply
- PFC & DC/DC Converter
- EV Charging Station
- UPS
- Renewable Energy
- Power Inverter & Motor Driver

Key Performance Parameters

Parameter	Symbol	Value	Unit
Drain-Source Voltage	$V_{DS} @ T_{j(max)}$	700	V
Recommended Gate-Source Turn-On Voltage	V_{GS}	15~18	
Drain-Source On-State Resistance	$R_{DS(on)}$	12	mΩ
Continuous Drain Current	I_D	140	A
Pulse Drain Current	$I_{D, pulse}$	607	
Power Dissipation	P_{tot}	375	W
Avalanche Energy	E_{AS}	2950	mJ
Gate Charge	Q_G	315	nC
Output Capacitive Charge	Q_{oss}	301	
Junction & Storage Temperature	T_j, T_{stg}	-55 to 175	°C

Part Number	Package	Marking
FF06010FA	TOLL	FF06010A
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For further information about comparable products, please contact (www.fastsic.com).

Maximum Ratings: ($T_j = 25^\circ\text{C}$, unless otherwise specified)

Parameter	Symbol	Min.	Typ.	Max.	Unit	Test Conditions
Drain-Source Voltage	V_{DS}	650	--	--	V	$V_{GS}=0\text{V}$, $I_D=100\mu\text{A}$
Continuous Drain Current	I_D	--	--	140 101	A	$V_{GS}=18\text{V}$, $T_c=25^\circ\text{C}$ $V_{GS}=18\text{V}$, $T_c=100^\circ\text{C}$
Pulse Drain Current	$I_{D,pulse}$	--	--	607		Per Fig. 13
Continuous Body Diode Current	I_S	--	--	81		$V_{GS}=0\text{V}$, $T_c=25^\circ\text{C}$
Avalanche Energy, Single Pulse	E_{AS}	--	--	2950	mJ	$L=25\text{mH}$
Operate Gate Source Voltage	$V_{GS,op}$	-8~0	--	15~18	V	Recommended operating values
Transient Gate Source Voltage	$V_{GS,tran.}$	-10	--	22		Transient operating limit (AC $f > 1\text{Hz}$, pulse width $< 100\text{ns}$)
Power Dissipation	P_{tot}	--	--	375	W	$T_c=25^\circ\text{C}$
Junction Temperature	T_j	-55	--	175	$^\circ\text{C}$	--
Storage Temperature	T_{stg}	-55	--	175		
Soldering Temperature	T_L	--	--	260		

Electrical Characteristics:

Parameter	Symbol	Min.	Typ.	Max.	Unit	Test Conditions
DC Characteristics (at $T_j = 25^\circ\text{C}$, unless otherwise specified)						
Drain-source Breakdown Voltage	$V_{(BR)DSS}$	650 --	-- 700	-- --	V	$V_{GS}=0\text{V}$, $I_D=100\mu\text{A}$, $T_j=25^\circ\text{C}$ $V_{GS}=0\text{V}$, $I_D=100\mu\text{A}$, $T_j=175^\circ\text{C}$
Drain-Source On-State Resistance	$R_{DS(on)}$	-- --	12 16	18 --	m Ω	$V_{GS}=18\text{V}$, $I_D=60\text{A}$, $T_j=25^\circ\text{C}$ $V_{GS}=18\text{V}$, $I_D=60\text{A}$, $T_j=175^\circ\text{C}$
Gate-Source Threshold Voltage	V_{th}	--	2.5	--	V	$V_{GS}=V_{DS}$, $I_D=100\text{mA}$
Zero Gate Voltage Drain Current	I_{DSS}	--	10	60	μA	$V_{DS}=650\text{V}$, $V_{GS}=0\text{V}$, $T_j=25^\circ\text{C}$
Gate-Source Leakage Current	I_{GSS}	--	--	100	nA	$V_{GS}=18\text{V}$, $V_{DS}=0\text{V}$
Body Diode Forward Voltage	V_{SD}	-- --	2.9 2.5	-- --	V	$V_{GS}=0\text{V}$, $I_S=30\text{A}$, $T_j=25^\circ\text{C}$ $V_{GS}=0\text{V}$, $I_S=30\text{A}$, $T_j=175^\circ\text{C}$
AC Characteristics (at $T_j = 25^\circ\text{C}$, unless otherwise specified)						
Input Capacitance	C_{iss}	--	7390	--	pF	$V_{DS}=400\text{V}$, $V_{GS}=0\text{V}$, $f=250\text{kHz}$, $V_{AC}=25\text{mV}$
Output Capacitance	C_{oss}	--	525	--		
Reverse Capacitance	C_{rss}	--	74	--		
Effective Output Capacitance, energy related	$C_{o(er)}^1$	--	1009	--		
Effective Output Capacitance, time related	$C_{o(tr)}^2$	--	800	--		
C_{oss} Stored Energy	E_{oss}	--	71	--	μJ	
Output Capacitive Charge	Q_{oss}	--	301	--	nC	
Internal Gate Resistance	$R_{G,int.}$	--	1.6	--	Ω	$f=1\text{MHz}$, $V_{AC}=25\text{mV}$

¹ $C_{o(er)}$ is a fixed capacitance that gives the same stored energy as C_{oss} while V_{DS} is rising from 0 to 400V.

² $C_{o(tr)}$ is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 to 400V.

Switching Characteristics:

Parameter	Symbol	Min.	Typ.	Max.	Unit	Test Conditions
Gate Characteristics						
Gate to Source Charge	Q_{GS}	--	58	--	nC	V_{DS} =400V, V_{GS} =0V/15V, I_D =60A
Gate to Drain Charge	Q_{GD}	--	120	--		
Total Gate Charge	Q_G	--	315	--		
Inductive Load						
Turn On Delay Time	$t_{d(on)}$	--	101	--	ns	V_{DS} =400V, I_D =85A, V_{GS} =-3/+15V, $R_{G(ext.)}$ = 5.4Ω External SiC Diode as an FWD
Rise Time	t_r	--	139	--		
Turn Off Delay Time	$t_{d(off)}$	--	42	--		
Fall Time	t_f	--	31	--		
Turn On Switching Energy	E_{on}	--	2246	--	μJ	
Turn Off Switching Energy	E_{off}	--	810	--		
Resistive Load						
Turn On Delay Time	$t_{d(on)}$	--	20	--	ns	V_{DS} =400V, I_D =100A, V_{GS} =-3/+15V, $R_{G_{on, ext.}}$ = 5.4Ω , $R_{G_{off, ext.}}$ = 1Ω R_L =4Ω
Rise Time	t_r	--	75	--		
Turn Off Delay Time	$t_{d(off)}$	--	28	--		
Fall Time	t_f	--	31	--		
Body Diode Characteristics						
Reverse Recovery Charge	Q_{rr}	--	648	--	nC	V_{GS} =0V, I_S =80A, V_{DS} =400V, di/dt =1115A/μs * Q_{rr} herein excluded the Q_{oss} value.
Reverse Recovery Time	t_{rr}	--	51	--	ns	
Peak Reverse Recovery Current	I_{rrm}	--	25.6	--	A	

Thermal Characteristics:

Parameter	Symbol	Min.	Typ.	Max.	Unit	Test Conditions
Thermal Impedance, junction-case	R_{th-jc}	--	0.4	--	K/W	--
Thermal Impedance, junction-ambient	R_{th-ja}	--	40	--		Device on PCB, with 6 cm ² of cooling area

Electrical Characteristics Diagrams

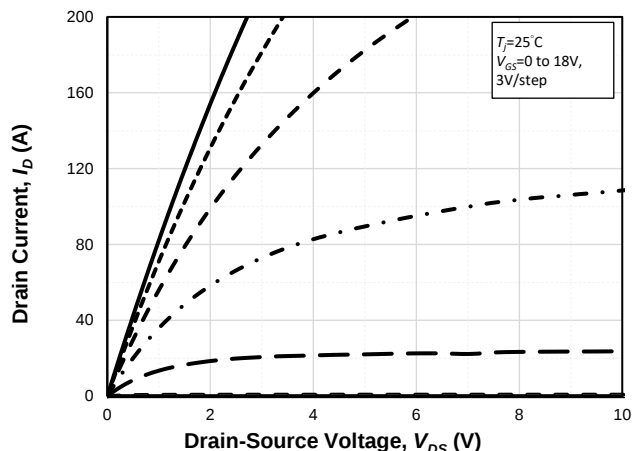


Fig. 1 Typical Output Characteristics at $T_j = 25^\circ\text{C}$

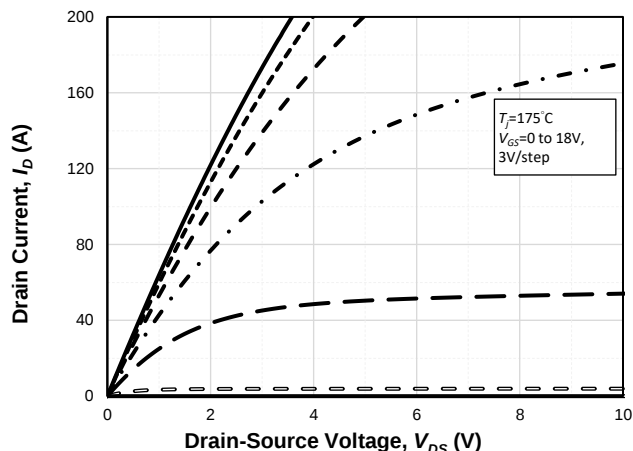


Fig. 2 Typical Output Characteristics at $T_j = 175^\circ\text{C}$

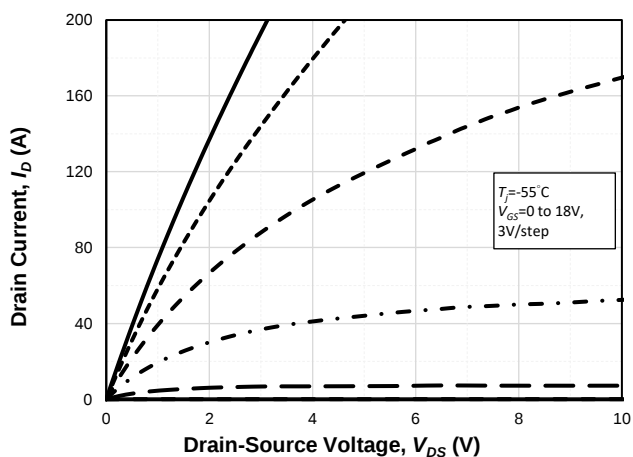


Fig. 3 Typical Output Characteristics at $T_j = -55^\circ\text{C}$

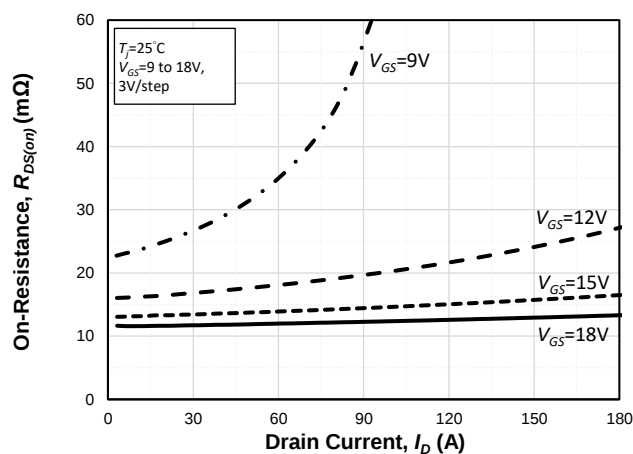


Fig. 4 Typ. $R_{DS(on)}$ vs. I_D with Various V_{GS}

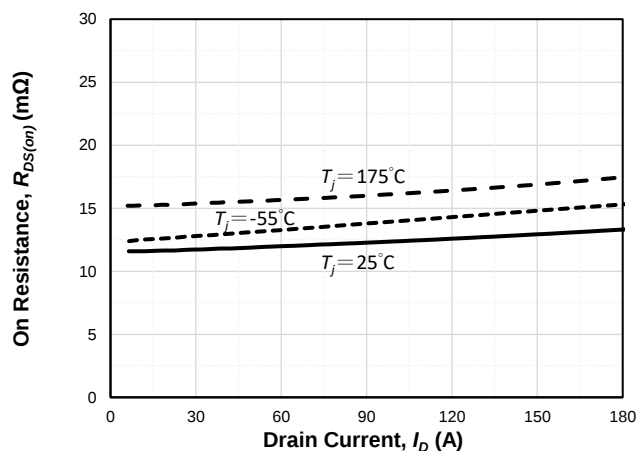


Fig. 5 Typ. $R_{DS(on)}$ vs. I_D with Various T_j , $V_{GS} = 18\text{V}$

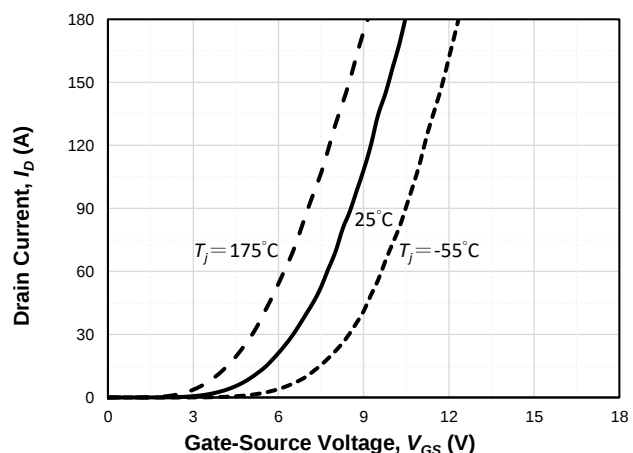


Fig. 6 Typ. I_D vs. V_{GS} with Various T_j , $V_{DS} = 10\text{V}$

Electrical Characteristics Diagrams

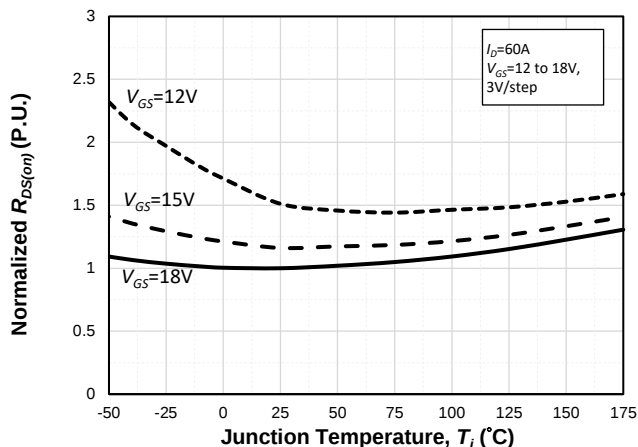


Fig. 7 Normalized $R_{DS(on)}$ vs. T_J with Various V_{GS}

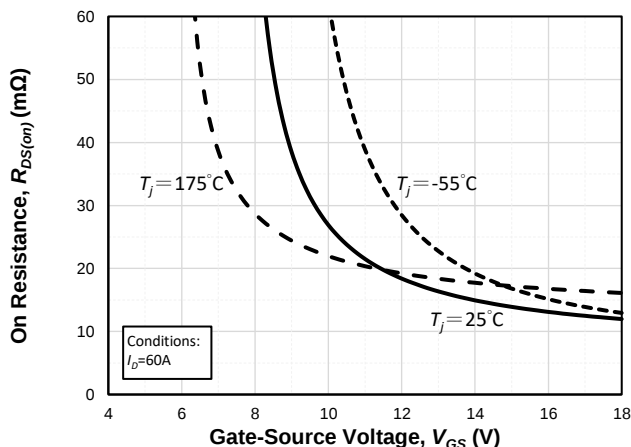


Fig. 8 Typ. $R_{DS(on)}$ vs. V_{GS} with Various T_J

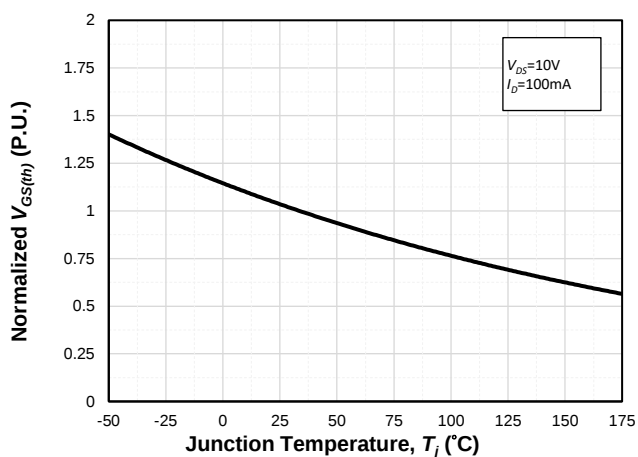


Fig. 9 Normalized V_{th} vs. T_J

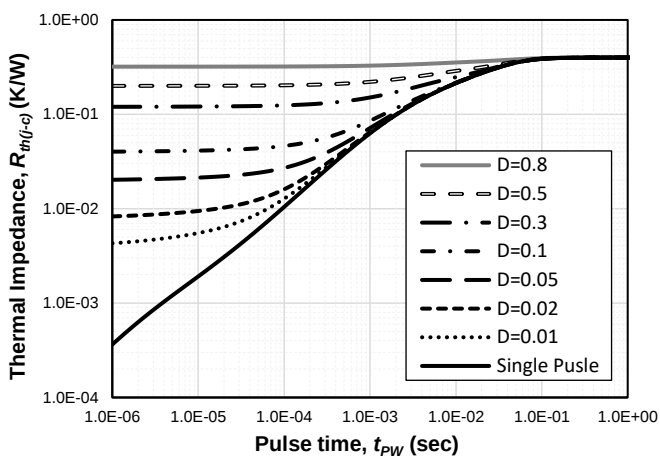


Fig. 10 Typ. Transient Thermal Impedance R_{th-jc}

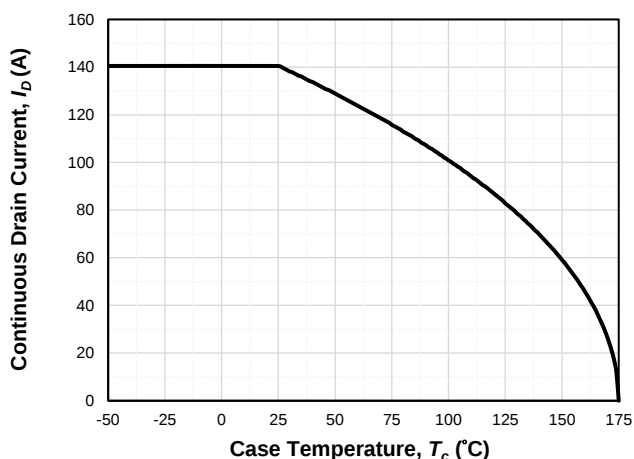


Fig. 11 Continuous I_D De-rating at $V_{GS} = 18V$, $T_J \leq 175°C$

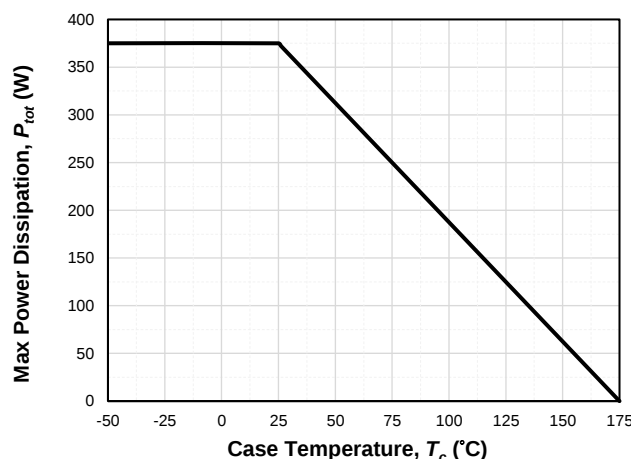


Fig. 12 Power Dissipation at $V_{GS} = 18V$, $T_J \leq 175°C$

Electrical Characteristics Diagrams

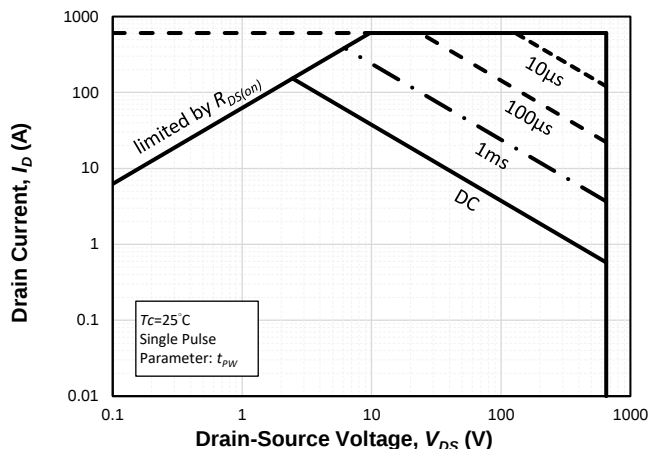


Fig. 13 Safe Operating Area at $T_c=25^\circ\text{C}$

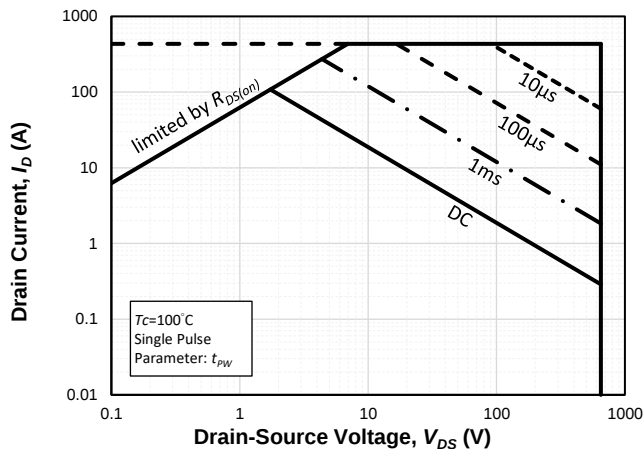


Fig. 14 Safe Operating Area at $T_c=100^\circ\text{C}$

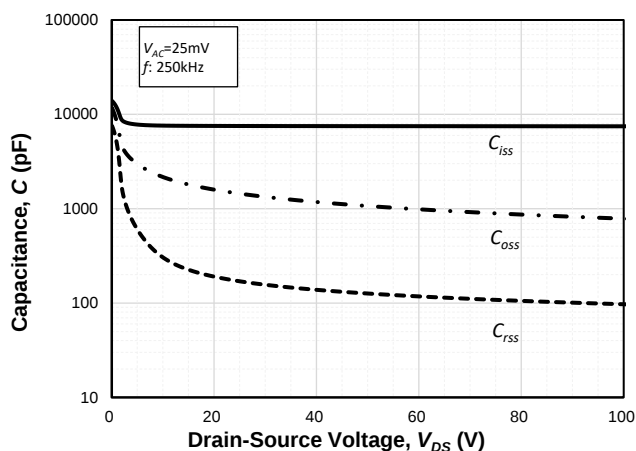


Fig. 15 Typ. Capacitance vs. V_{DS} at $f_{sw}=250\text{kHz}$, $V_{DS}\leq 100\text{V}$

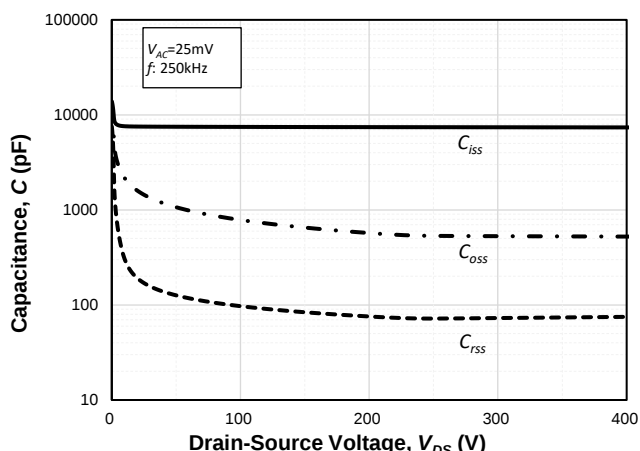


Fig. 16 Typ. Capacitance vs. V_{DS} at $f_{sw}=250\text{kHz}$, $V_{DS}\leq 400\text{V}$

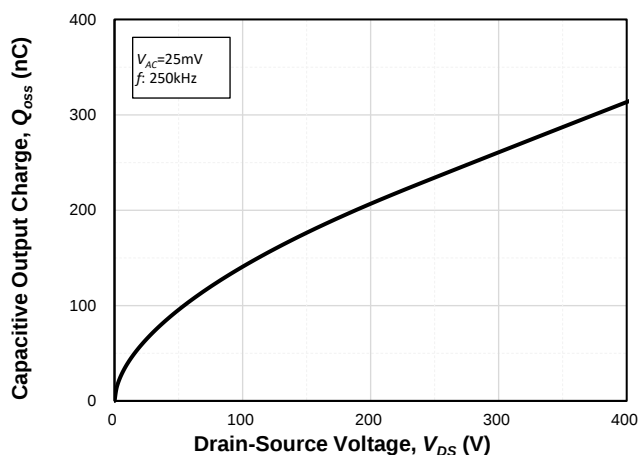


Fig. 17 Typ. Capacitive Output Charge at $f_{sw}=250\text{kHz}$

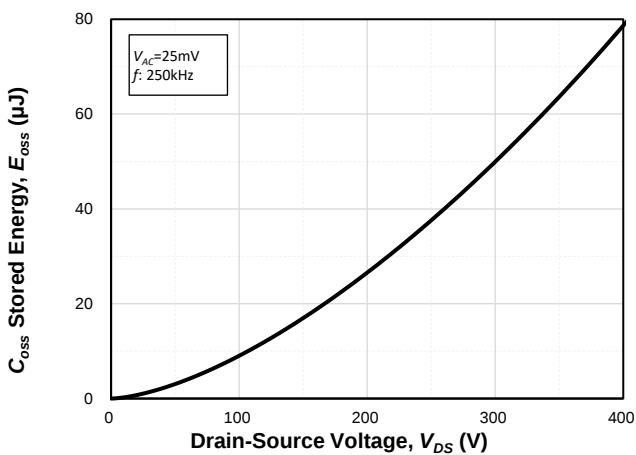


Fig. 18 Typ. C_{oss} Stored Energy at $f_{sw}=250\text{kHz}$

Electrical Characteristics Diagrams

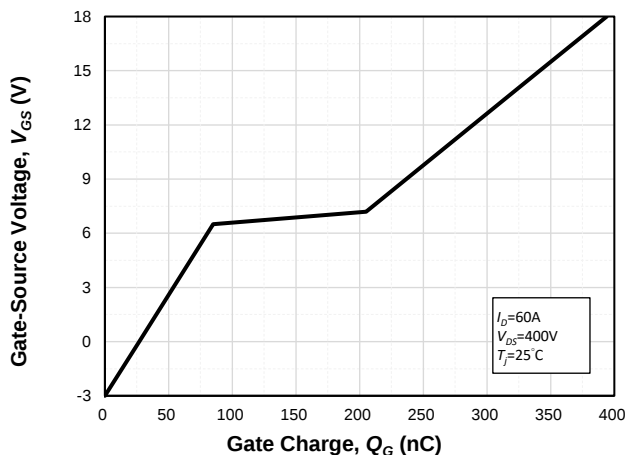


Fig. 19 Typ. Gate Charge at $V_{DS}=400V$, $I_D=40A$

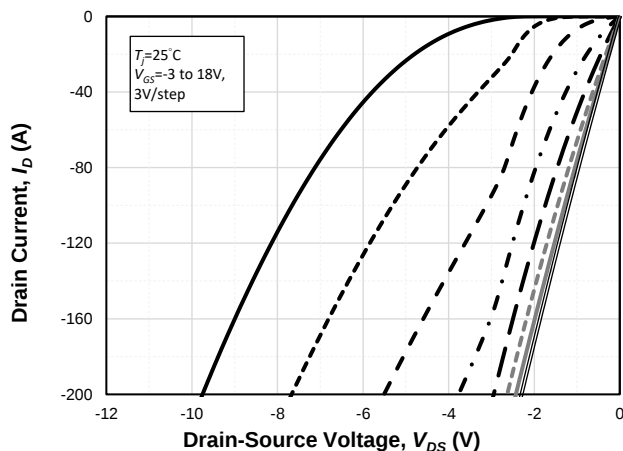


Fig. 20 Typical Forward Characteristics of Reverse Conduction at $T_J=25^\circ C$

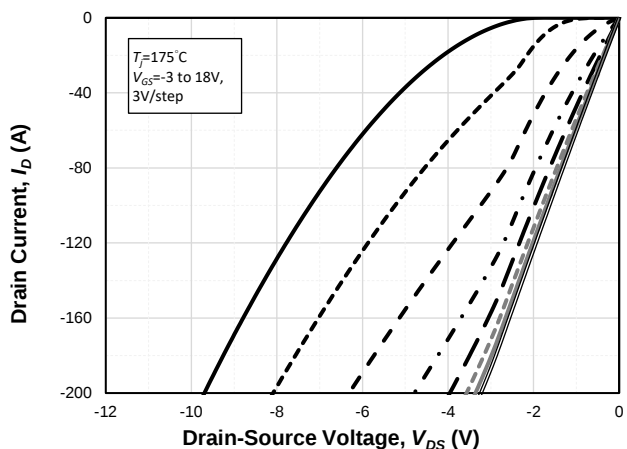


Fig. 21 Typical Forward Characteristics of Reverse Conduction at $T_J=175^\circ C$

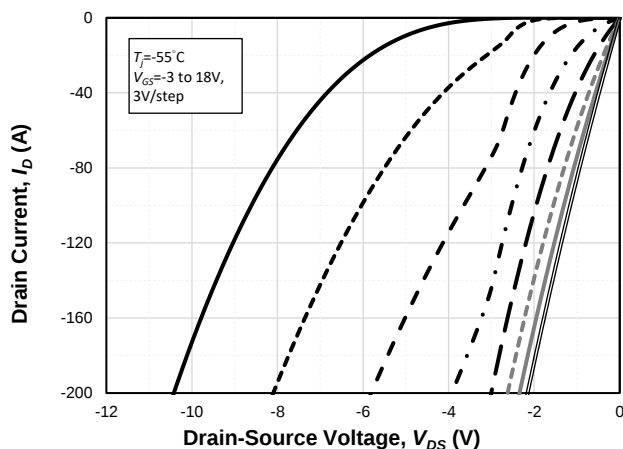


Fig. 22 Typical Forward Characteristics of Reverse Conduction at $T_J=55^\circ C$

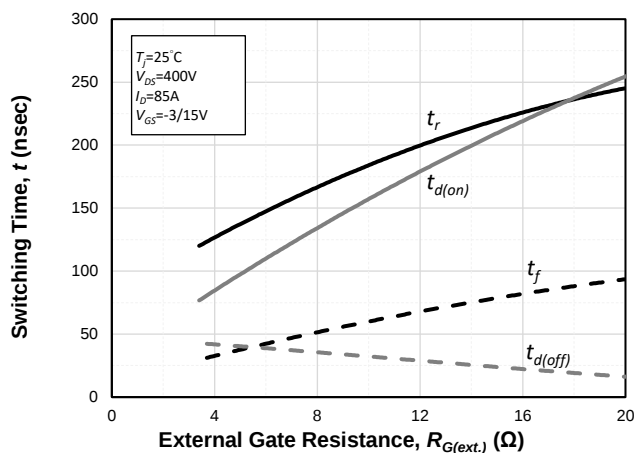


Fig. 23 Typ. Switching Time vs. $R_{G(ext.)}$

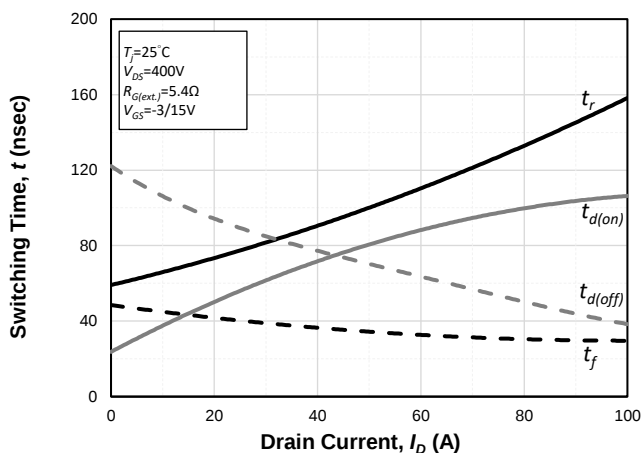


Fig. 24 Typ. Switching Time vs. I_D

Electrical Characteristics Diagrams

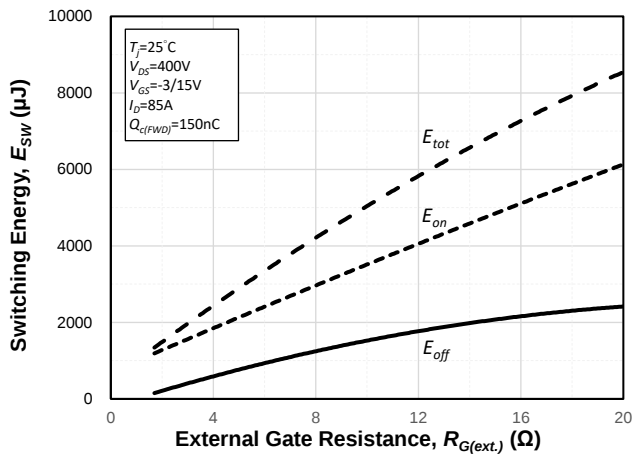


Fig. 25 Typ. Switching Energy vs. $R_{G(ext.)}$

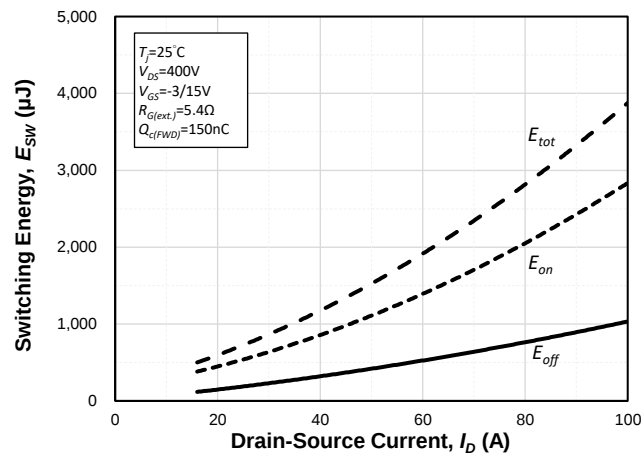
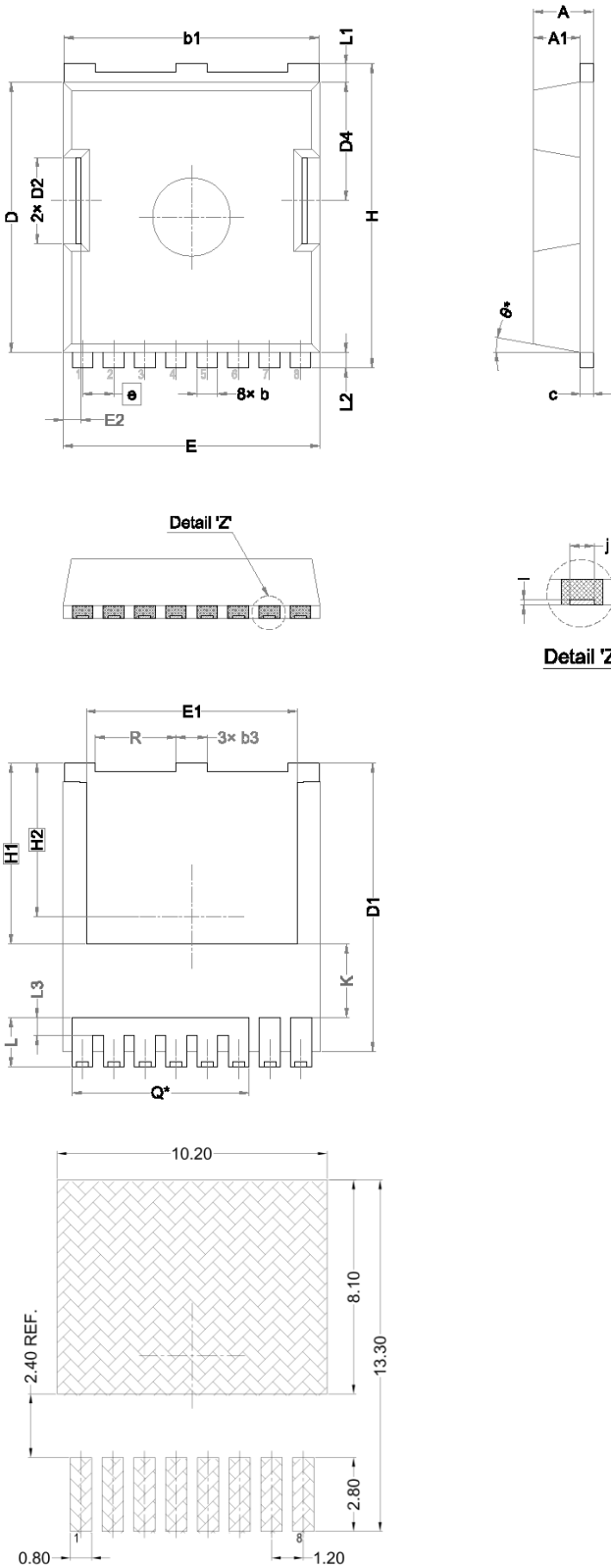


Fig. 26 Typ. Switching Energy vs. I_D

Package Outline (TOLL, MO-299B)



Land Pattern (Only for reference)

Symbol	Dimension (Millimeters)		
	Min.	Nom.	Max.
A	2.20	2.30	2.40
A1	1.70	1.80	1.90
b	0.70	0.80	0.90
b1	9.70	9.80	9.90
b3	1.10	1.20	1.30
c	0.40	0.50	0.60
D	10.28	10.38	10.48
D1	10.98	11.08	11.18
D2	3.20	3.30	3.40
D4	4.45	4.55	4.65
E	9.80	9.90	10.00
E1	8.00	8.10	8.20
E2	0.60	0.70	0.80
e	1.20 BSC.		
H	11.58	11.68	11.78
H1	6.95 BSC.		
H2	5.89 BSC.		
i	0.10 REF.		
j	0.46 REF.		
K	2.80 REF.		
L	1.40	1.90	2.10
L1	0.60	0.70	0.80
L2	0.50	0.60	0.70
L3	0.30	0.70	0.80
N	8		
Q	6.80 REF.		
R	3.00	3.10	3.20
θ	10° REF.		

- Note:**
1. Dimensions do not inclusive burrs and mold flash.
 2. “*” is for reference.

Revision History

Date	Revision	Changes
23.08	Preliminary	1 st issue
24.05	Preliminary	Update dynamic characteristics
24.11	Preliminary	Update pad layout

Important Note (Disclaimer)

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